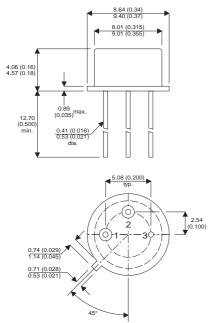


2N6802 **IRFF430** 

#### **MECHANICAL DATA** Dimensions in mm (inches)



## **N–CHANNEL ENHANCEMENT MODE POWER MOSFET**

$BV_{DSS}$	500V
I <sub>D(cont)</sub>	2.5
R <sub>DS(on)</sub>	1.5Ω

### **FEATURES**

- AVALANCHE ENERGY RATED
- HERMETICALLY SEALED
- DYNAMIC dv/dt RATING
- SIMPLE DRIVE REQUIREMENTS

**Underside View** Pin 1 – Source Pin 2 - Gate Pin 3 – Drain

TO39 – Package (TO-205AF)

### ABSOLUTE MAXIMUM RATINGS (T<sub>case</sub> = 25°C unless otherwise stated)

	6466	-		
V <sub>GS</sub>	Gate – Source Voltage	±20V		
I <sub>D</sub>	Continuous Drain Current $(V_{GS} = 10V, T_{case} = 25^{\circ}C)$	2.5A		
I <sub>D</sub>	Continuous Drain Current $(V_{GS} = 10V, T_{case} = 100^{\circ}C)$	1.5A		
I <sub>DM</sub>	Pulsed Drain Current <sup>1</sup>	11A		
P <sub>D</sub>	Power Dissipation @ T <sub>case</sub> = 25°C	25W		
	Linear Derating Factor	0.2W/°C		
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>2</sup>	0.35mJ		
dv/dt	Peak Diode Recovery <sup>3</sup>	3.5V/ns		
T <sub>J</sub> , T <sub>stg</sub>	Operating and Storage Temperature Range	–55 to +150°C		
$R_{\theta JC}$	Thermal Resistance Junction to Case	5.0°C/W		
$R_{ extsf{ heta}JA}$	Thermal Resistance Junction-to-Ambient	175°C/W		

#### Notes

1) Pulse Test: Pulse Width  $\leq$  300 $\mu$ s,  $\delta \leq$  2%

2) @ V<sub>DD</sub> = 50V , Peak I<sub>L</sub> = 2.5A , Starting T<sub>J</sub> = 25°C

3) @ I\_{SD}  $\leq 2.5A$  , di/dt  $\leq 75A/\mu s$  , V\_{DD}  $\leq BV_{DSS}$  , T\_J  $\leq 150^\circ C$  , SUGGESTED R\_G = 7.5  $\Omega$ 

Semelab Plc reserves the right to change test conditions, parameter limits and package dimensions without notice. Information furnished by Semelab is believed to be both accurate and reliable at the time of going to press. However Semelab assumes no responsibility for any errors or omissions discovered in its use. Semelab encourages customers to verify that datasheets are current before placing orders.

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# 2N6802 IRFF430

### ELECTRICAL CHARACTERISTICS (T<sub>amb</sub> = 25°C unless otherwise stated)

	Parameter	Test Conditions		Min.	Тур.	Max.	Unit		
	STATIC ELECTRICAL RATINGS						4		
BV <sub>DSS</sub>	Drain – Source Breakdown Voltage	$V_{GS} = 0$	I <sub>D</sub> = 1mA	500			V		
$\Delta BV_{DSS}$	Temperature Coefficient of	Reference to 25	5°C		0.43		V/°C		
$\Delta T_{J}$	Breakdown Voltage	I <sub>D</sub> = 1mA			0.43		V/ C		
R <sub>DS(on)</sub>	Static Drain – Source On–State	$V_{GS} = 10V$	I <sub>D</sub> = 1.5A			1.5	Ω		
	Resistance	$V_{GS} = 10V$	I <sub>D</sub> = 2.5A			1.725			
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$	I <sub>D</sub> = 250μA	2		4	V		
9 <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> > 15V	I <sub>DS</sub> = 1.5A	1.5			<b>S</b> (Ω)		
	Zero Gate Voltage Drain Current	$V_{GS} = 0$	$V_{DS} = 0.8 B V_{DSS}$			25	μΑ		
IDSS			T <sub>J</sub> = 125°C			250			
I <sub>GSS</sub>	Forward Gate – Source Leakage	$V_{GS} = 20V$				100	nA		
I <sub>GSS</sub>	Reverse Gate – Source Leakage	$V_{GS} = -20V$				-100			
	DYNAMIC CHARACTERISTICS				11				
C <sub>iss</sub>	Input Capacitance	$V_{GS} = 0$			610				
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 25V			135		pF		
C <sub>rss</sub>	Reverse Transfer Capacitance	f = 1MHz			65				
Qg	Total Gate Charge	$V_{GS} = 10V$		19.8		29.5			
Q <sub>gs</sub>	Gate – Source Charge	$V_{DS} = 0.5BV_{DS}$		2.2		4.6	nC		
Q <sub>gd</sub>	Gate – Drain ("Miller") Charge	I <sub>D</sub> = 2.5A		5.5		19.7			
t <sub>d(on)</sub>	Turn–On Delay Time	I <sub>D</sub> =2.5A				30			
t <sub>r</sub>	Rise Time	$V_{DS} = 0.5 BV_{DS}$	<sub>DS</sub> = 0.5BV <sub>DS</sub>			30			
t <sub>d(off)</sub>	Turn–Off Delay Time	R <sub>G</sub> = 7.5Ω				55	ns		
t <sub>f</sub>	Fall Time	_				30			
	SOURCE – DRAIN DIODE CHARAC	TERISTICS					4		
I <sub>S</sub>	Continuous Source Current					2.5	A		
I <sub>SM</sub>	Pulse Source Current <sup>2</sup>	I <sub>S</sub> = 2.5A	$V_{GS} = 0$			11			
V <sub>SD</sub>	Diode Forward Voltage	I <sub>F</sub> = 1.5A	T <sub>J</sub> = 25°C			1.4	V		
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 2.5A	$T_J = 25^{\circ}C$			900	ns		
Q <sub>rr</sub>	Reverse Recovery Charge	<sup>−</sup> d <sub>i</sub> / d <sub>t</sub> ≤ 100A/με	$V_{DD} \le 50V$			7.0	μC		
t <sub>on</sub>	Forward Turn-On Time				Negligible				

Notes

1) Pulse Test: Pulse Width  $\leq$  300 $\mu$ s,  $\delta \leq$  2%

2) Repetitive Rating – Pulse width limited by maximum junction temperature.

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